

SN54ALS273, SN74ALS273 OCTAL D-TYPE FLIP-FLOPS WITH CLEAR

SDAS218A – APRIL 1982 – REVISED DECEMBER 1994

- Contain Eight Flip-Flops With Single-Rail Outputs
- Buffered Clock and Direct-Clear Inputs
- Individual Data Input to Each Flip-Flop
- Applications Include:
 - Buffer/Storage Registers
 - Shift Registers
 - Pattern Generators
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

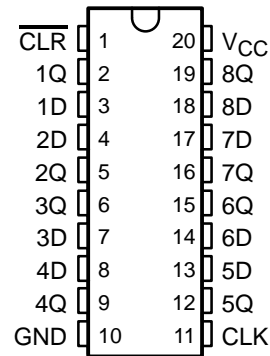
description

These octal positive-edge-triggered flip-flops utilize TTL circuitry to implement D-type flip-flop logic with a direct-clear ($\overline{\text{CLR}}$) input.

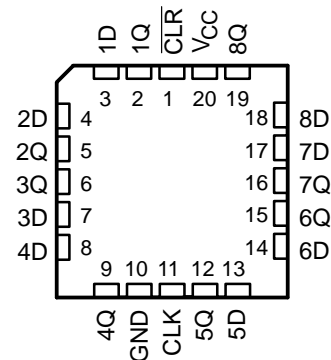
Information at the data (D) inputs meeting the setup-time requirements is transferred to the Q outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When CLK is at either the high or low level, the D input signal has no effect at the output.

The SN54ALS273 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ALS273 is characterized for operation from 0°C to 70°C .

SN54ALS273 . . . J PACKAGE
SN74ALS273 . . . DW OR N PACKAGE
(TOP VIEW)



SN54ALS273 . . . FK PACKAGE
(TOP VIEW)



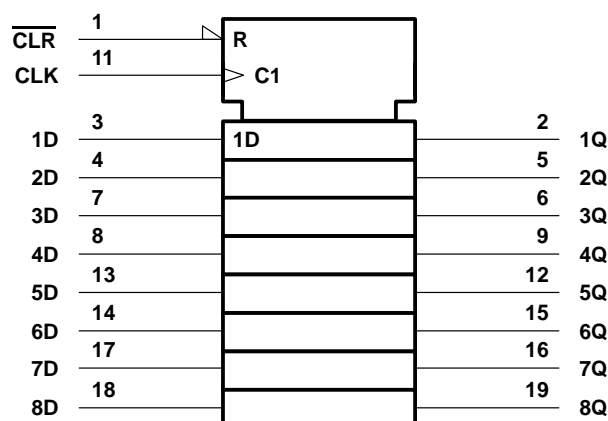
FUNCTION TABLE
(each flip-flop)

INPUTS			OUTPUT Q
$\overline{\text{CLR}}$	CLK	D	
L	X	X	L
H	\uparrow	H	H
H	\uparrow	L	L
H	H or L	X	Q_0

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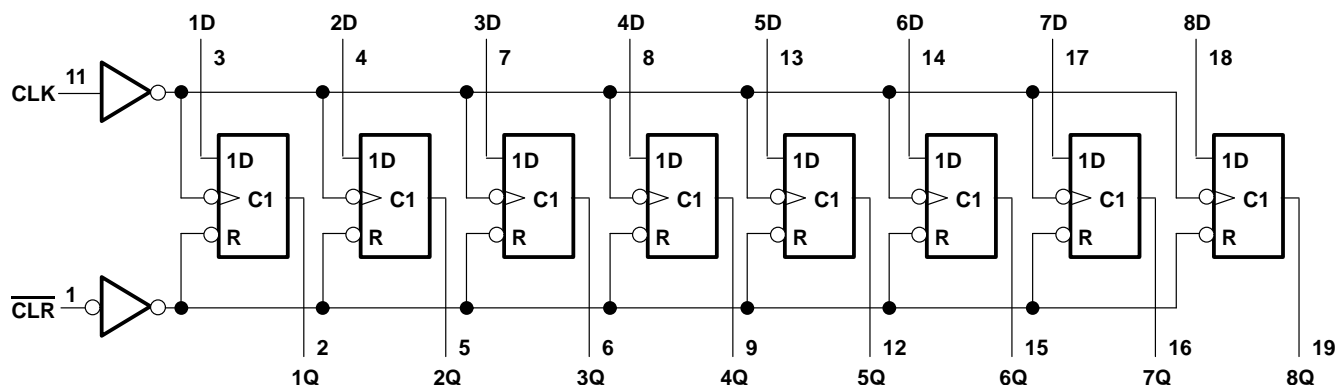
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V_{CC}	7 V
Input voltage, V_I	7 V
Operating free-air temperature range, T_A : SN54ALS273	–55°C to 125°C
SN74ALS273	0°C to 70°C
Storage temperature range	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

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recommended operating conditions

		SN54ALS273			SN74ALS273			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V _{IH}	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.7			0.8	V
I _{OH}	High-level output current			−1			−2.6	mA
I _{OL}	Low-level output current			12			24	mA
f _{clock}	Clock frequency	0		30	0		35	MHz
t _w	Pulse duration	$\overline{\text{CLR}}$ low		10	10		ns	
		CLK high		16.5	14			
		CLK low		16.5	14			
t _{su}	Setup time before CLK↑	Data		10	10		ns	
		$\overline{\text{CLR}}$ inactive state		15	15			
t _h	Hold time, data after CLK↑	0			0		ns	
T _A	Operating free-air temperature	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54ALS273			SN74ALS273			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}	$V_{CC} = 4.5\text{ V}$, $I_I = -18\text{ mA}$				–1.5			–1.5	V
V_{OH}	$V_{CC} = 4.5\text{ V to } 5.5\text{ V}$, $I_{OH} = -0.4\text{ mA}$		$V_{CC} - 2$			$V_{CC} - 2$			V
	$V_{CC} = 4.5\text{ V}$	$I_{OH} = -1\text{ mA}$	2.4	3.3					
		$I_{OH} = -2.6\text{ mA}$				2.4	3.2		
V_{OL}	$V_{CC} = 4.5\text{ V}$	$I_{OL} = 12\text{ mA}$		0.25	0.4		0.25	0.4	V
		$I_{OL} = 24\text{ mA}$					0.35	0.5	
I_I	$V_{CC} = 5.5\text{ V}$, $V_I = 7\text{ V}$				0.1			0.1	mA
I_{IH}	$V_{CC} = 5.5\text{ V}$, $V_I = 2.7\text{ V}$				20			20	μA
I_{IL}	$V_{CC} = 5.5\text{ V}$, $V_I = 0.4\text{ V}$				–0.2			–0.2	mA
$I_{O\ddagger}$	$V_{CC} = 5.5\text{ V}$, $V_O = 2.25\text{ V}$		–20		–112	–30		–112	mA
I_{CCH}	$V_{CC} = 5.5\text{ V}$			11	20		11	20	mA
I_{CCL}	$V_{CC} = 5.5\text{ V}$			19	29		19	29	mA

† All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .



SN54ALS273, SN74ALS273

OCTAL D-TYPE FLIP-FLOPS

WITH CLEAR

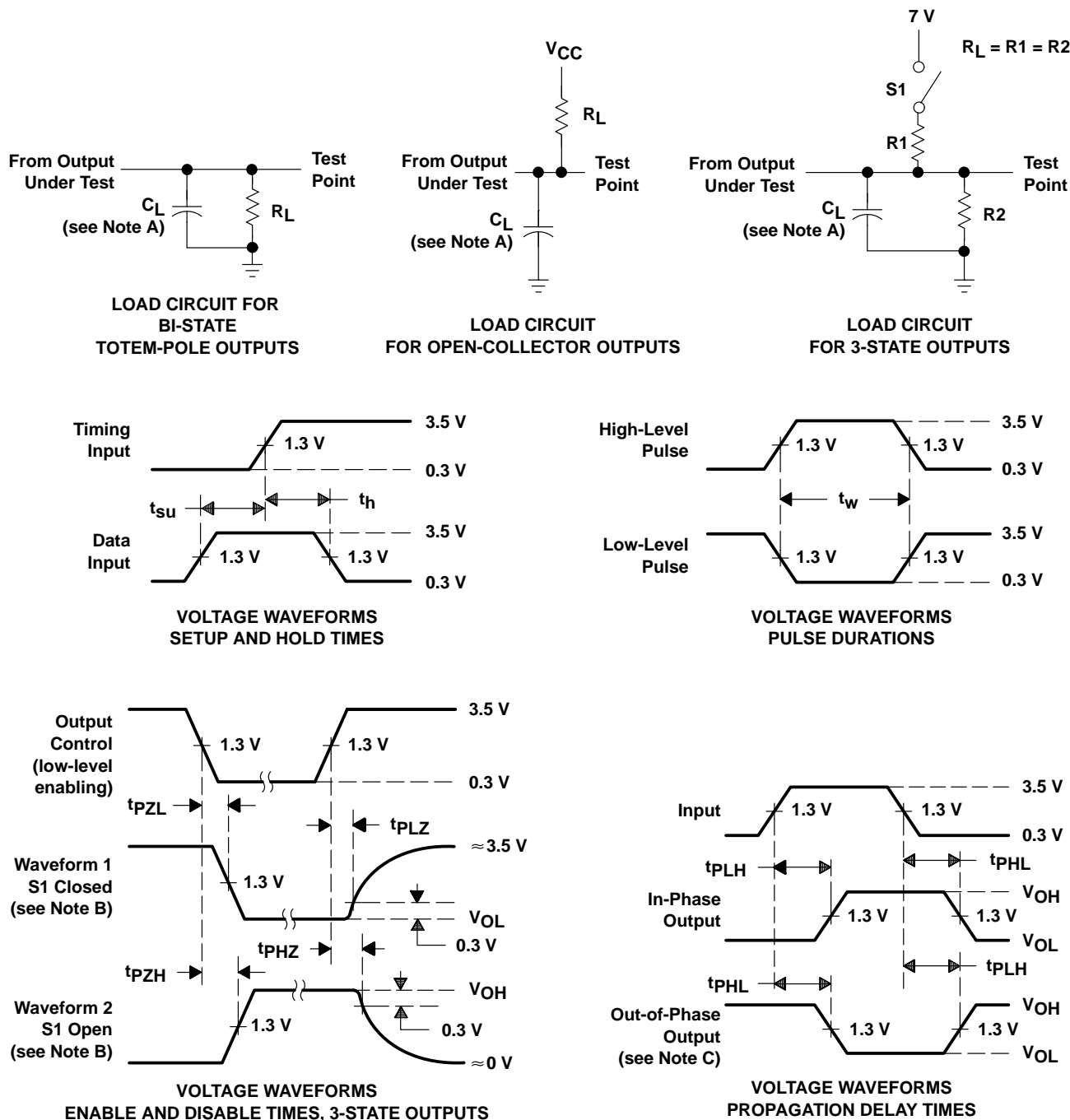
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switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX†				UNIT
			SN54ALS273		SN74ALS273		
			MIN	MAX	MIN	MAX	
f _{max}			30		35		MHz
t _{PHL}	$\overline{\text{CLR}}$	Any Q	4	24	4	18	ns
t _{PLH}	CLK	Any Q	2	20	2	12	ns
t _{PHL}			3	17	3	15	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

PARAMETER MEASUREMENT INFORMATION
SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
D. All input pulses have the following characteristics: $PRR \leq 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

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